## Notice of References Cited Application/Control No. 09/819,925 Examiner Hoan H. Tran Applicant(s)/Patent Under Reexamination HIRST ET AL. Page 1 of 1 U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0063916	04-2003	Katayanagi et al.	399/44
*	В	US-2004/0086306	05-2004	Edahiro et al.	399/328
	С	US-			
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	н	US-			
	ı	US-			
	J	US-			
	К	US-			
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## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	Р			,		
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	R					
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## **NON-PATENT DOCUMENTS**

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